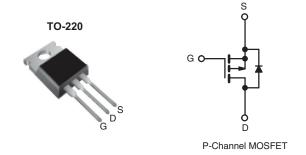
COMPLIANT





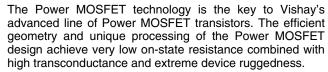
PRODUCT SUMMARY					
V _{DS} (V)	- 50				
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = - 10 V	0.33			
Q _g (Max.) (nC)	26				
Q _{gs} (nC)	6.2				
Q _{gd} (nC)	8.6				
Configuration	Single				



FEATURES

- · P-Channel Versatility
- · Compact Plastic Package
- · Fast Switching
- Low Drive Current
- Ease of Paralleling
- Excellent Temperature Stability
- Lead (Pb)-free Available

DESCRIPTION



The P-Channel Power MOSFET's are designed for application which require the convenience of reverse polarity operation. They retain all of the features of the more common N-Channel Power MOSFET's such as voltage control, very fast switching, ease of paralleling, and excellent temperature stability.

P-Channel Power MOSFETs are intended for use in power stages where complementary symmetry with N-Channel devices offers circuit simplification. They are also very useful in drive stages because of the circuit versatility offered by the reverse polarity connection. Applications include motor control, audio amplifiers, switched mode converters, control circuits and pulse amplifiers.

ORDERING INFORMATION			
Package	TO-220		
Lead (Pb)-free	IRF9Z22PbF		
	SiHF9Z22-E3		
SnPb	IRF9Z22		
	SiHF9Z22		

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V_{DS}	- 50	V	
Gate-Source Voltage			V_{GS}	± 20		
Drain-Gate Voltage (R_{GS} = 20 KΩ)			V_{GDR}	- 50	1	
Continuous Drain Current	V at 10 V	$T_{\rm C} = 25 ^{\circ}{\rm C}$ $T_{\rm C} = 100 ^{\circ}{\rm C}$	1	- 8.9	А	
	VGS at - 10 V	T _C = 100 °C	- I _D	- 5.6		
Pulsed Drain Current ^a			I _{DM}	- 36		
Linear Derating Factor				0.32	W/°C	
Inductive Current, Clamped	L = 100 μH		I _{LM}	- 36	Α	
Unclamped Inductive Current (Avalanche Current)			ΙL	- 2.2	Α	
Maximum Power Dissipation	T _C = 25 °C		P_{D}	40	W	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d		

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 25 V, starting T_J = 25 °C, L =100 μ H, R_G = 25 Ω c. $I_{SD} \le$ 6.7 A, dl/dt \le 90 A/ μ s, $V_{DD} \le$ V_{DS} , $T_J \le$ 175 °C.

- d. 0.063" (1.6 mm) from case.
- * Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	80		
Case-to-Sink, Flat, Greased Surface	R _{thCS}	1.0	-	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.1		

PARAMETER	SYMBOL	TES	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V_{DS}	V _{GS} = 0 V, I _D = - 250 μA		- 50	-	-	V
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	$V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$		-	- 4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V		-	± 500	nA
Zero Gate Voltage Drain Current	l	$V_{DS} = m$	V_{DS} = max. rating, V_{GS} = 0 V V_{DS} = max. rating x 0,8, V_{GS} = 0 V, T_J =125°C		-	- 250	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = max. rati			-	- 1000	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = - 10 V	I _D = - 5.6 A ^b	-	0.28	0.33	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 2	$x V_{GS}, I_{DS} = -5.6 A^{b}$	2.3	3.5	-	S
Dynamic							
Input Capacitance	C _{iss}	V _{GS} = 0 V,		-	480	-	pF
Output Capacitance	C _{oss}		$V_{DS} = -25 \text{ V},$		320	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 9		=	58	-	
Total Gate Charge	Qg	V _{GS} = - 10 V		-	17	26	
Gate-Source Charge	Q _{gs}		-	4.1	6.2	nC	
Gate-Drain Charge	Q_{gd}		max. rating. see lig. 17	-	5.7	8.6	
Turn-On Delay Time	t _{d(on)}	V _{DD} = - 25 V, I _D = - 9.7 A,		-	8.2	12	- ns
Rise Time	t _r	$R_G = 18 \Omega$	$R_G=18~\Omega,~R_D=2.4~\Omega,~see~fig.~16$ (MOSFET switching times are essentially independent of operating		57	86	
Turn-Off Delay Time	t _{d(off)}				12	18	
Fall Time	t _f	temperature)		-	25	38	
Internal Drain Inductance	L _D	6 mm (0.25'	Between lead, 6 mm (0.25") from		4.5	-	- nH
Internal Source Inductance	L _S	package and center of die contact		-	7.5	-	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I _S	,	MOSFET symbol showing the		-	- 9.7	
Pulsed Diode Forward Current ^a	I _{SM}	integral reverse p - n junction diode		-	-	- 39	A
Body Diode Voltage	V _{SD}	T _J = 25 °C	, I _S = - 9.7 A, V _{GS} = 0 V ^b	-	-	- 6.3	V
Body Diode Reverse Recovery Time	t _{rr}	T 05 00 1			110	280	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$T_J = 25 ^{\circ}\text{C}$, $I_F = -9.7 \text{A}$, $dI/dt = 100 \text{A/µs}^{\text{b}}$		0.17	0.34	0.85	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_C					I L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μs ; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

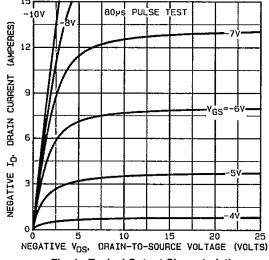
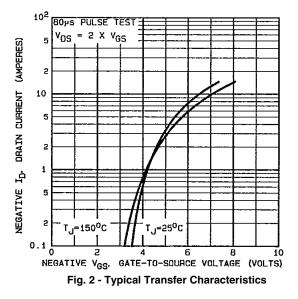


Fig. 1 - Typical Output Characteristics



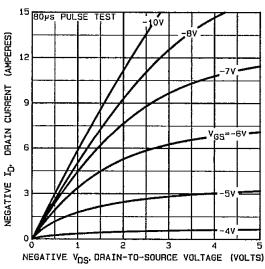
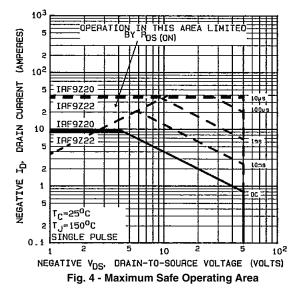


Fig. 3 - Typical Saturation Characteristics





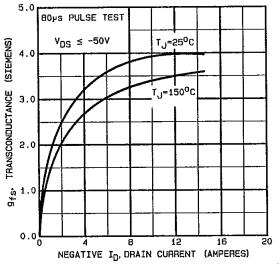


Fig. 5 - Typical Transconductance vs. Drain Current

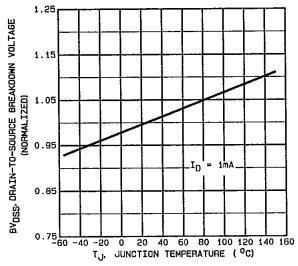


Fig. 7 - Typical Source-Drain Diode Forward Voltage

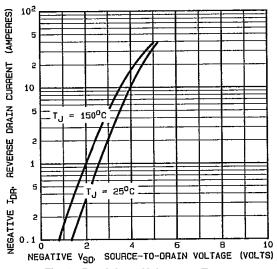


Fig. 6 - Breakdown Voltage vs. Temperature

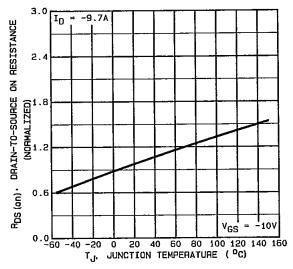


Fig. 8 - Normalized On-Resistance vs. Temperature



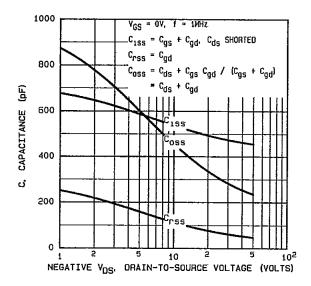


Fig. 9 - Typical Capacitance vs. Drain-to-Source Voltage

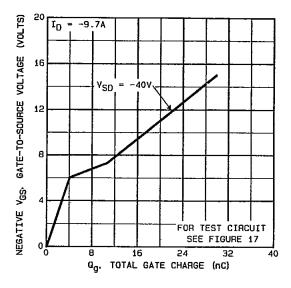


Fig. 10 - Typical Gate Charge vs. Gate-to-Source Voltage

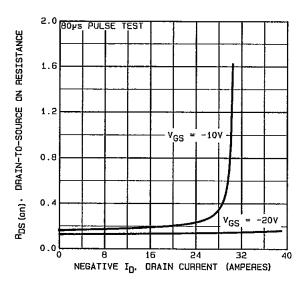


Fig. 11 - Typical Gate Charge vs. Gate-to-Source Voltage

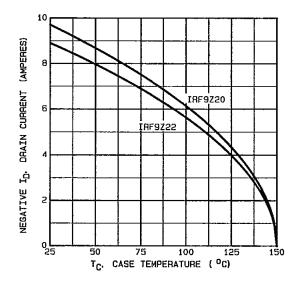


Fig. 12 - Maximum Drain Current vs. Case Temperature



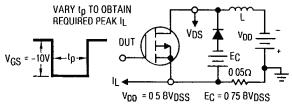


Fig. 13a - Clamped Inductive Test Circuit

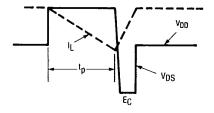


Fig. 13b - Clamped Inductive Waveforms

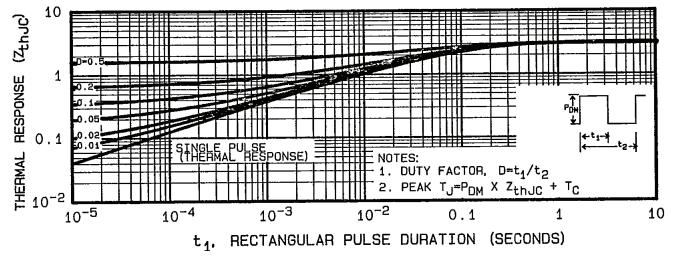


Fig. 14 - Maximum Effective Transient Thermal Impedance, Junction-to-Case vs. Pulse Duration

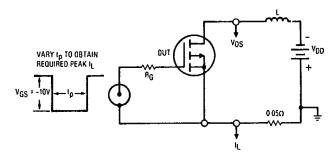


Fig. 15a - Unclamped Inductive Test Circuit

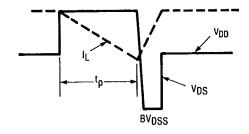


Fig. 15b - Unclamped Inductive Load Test Waveforms



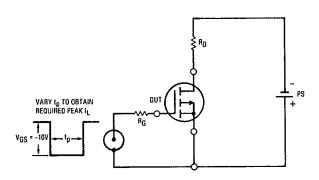


Fig. 16 - Switching Time Test Circuit

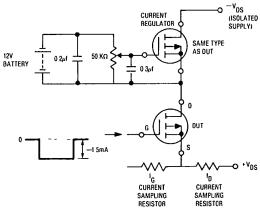


Fig. 17 - Gate Charge Test Circuit

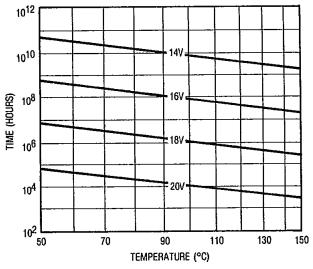


Fig. 18 - Typical Time to Accumulated 1 % Gate Failure

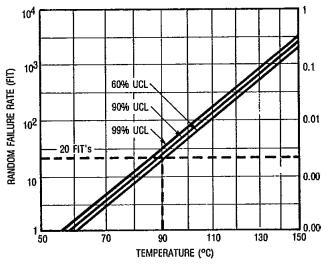
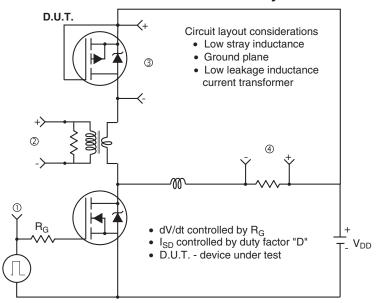


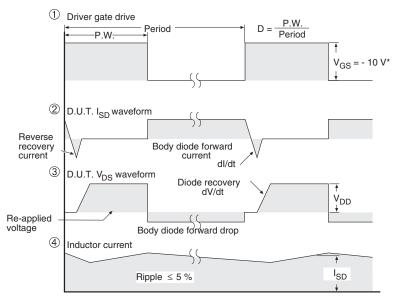
Fig. 19 - Typical High Temperature Reverse Bias (HTRB) Failure Rate



Peak Diode Recovery dV/dt Test Circuit



• Compliment N-Channel of D.U.T. for driver



* V_{GS} = - 5 V for logic level and - 3 V drive devices

Fig. 20 - For P-Channel

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